



May 1998

74LVQ138

Low Voltage 1-of-8 Decoder/Demultiplexer

General Description

The LVQ138 is a high-speed 1-of-8 decoder/demultiplexer. This device is ideally suited for high-speed bipolar memory chip select address decoding. The multiple input enables allow parallel expansion to a 1-of-24 decoder using just three LVQ138 devices or a 1-of-32 decoder using four LVQ138 devices and one inverter.

Features

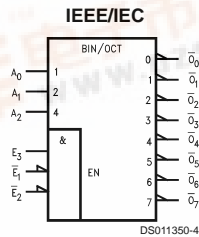
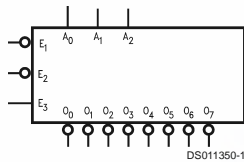
- Ideal for low power/low noise 3.3V applications
- Guaranteed simultaneous switching noise level and dynamic threshold performance
- Improved latch-up immunity
- Guaranteed incident wave switching into 75Ω
- 4 kV minimum ESD immunity
- Demultiplexing capability
- Multiple input enable for each expansion
- Active LOW mutually exclusive outputs

Ordering Code:

Order Number	Package Number	Package Description
74LVQ138SC	M16A	16-Lead (0.150" Wide) Small Outline Integrated Circuit, SOIC JEDEC
74LVQ138SJ	M16D	16-Lead Molded Small Outline Package, SOIC EIAJ

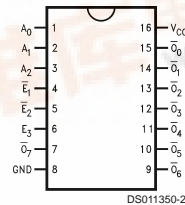
Devices also available in Tape and Reel. Specify by appending suffix letter "X" to the ordering code.

Logic Symbols



Connection Diagram

Pin Assignment for SOIC JEDEC and EIAJ



Pin Descriptions

Pin Names	Description
A ₀ -A ₂	Address Inputs
\bar{E}_1 - \bar{E}_2	Enable Inputs
E ₃	Enable Input
O ₀ -O ₇	Outputs

74LVQ138 Low Voltage 1-of-8 Decoder/Demultiplexer



Functional Description

The LVQ138 high-speed 1-of-8 decoder/demultiplexer accepts three binary weighted inputs (A_0, A_1, A_2) and, when enabled, provides eight mutually exclusive active-LOW outputs ($\bar{O}_0-\bar{O}_7$). The LVQ138 features three Enable inputs, two active-LOW (\bar{E}_1, \bar{E}_2) and one active-HIGH (E_3). All outputs will be HIGH unless \bar{E}_1 and \bar{E}_2 are LOW and E_3 is HIGH. This multiple enable function allows easy parallel expansion

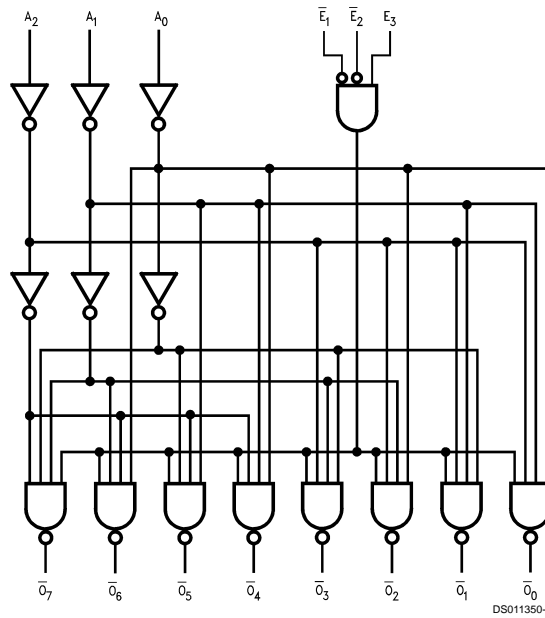
of the device to a 1-of-32 (5 lines to 32 lines) decoder with just four LVQ138 devices and one inverter (see *Figure 1*). The LVQ138 can be used as an 8-output demultiplexer by using one of the active LOW Enable inputs as the data input and the other Enable inputs as strobes. The Enable inputs which are not used must be permanently tied to their appropriate active-HIGH or active-LOW state.

Truth Table

Inputs						Outputs							
\bar{E}_1	\bar{E}_2	E_3	A_0	A_1	A_2	\bar{O}_0	\bar{O}_1	\bar{O}_2	\bar{O}_3	\bar{O}_4	\bar{O}_5	\bar{O}_6	\bar{O}_7
H	X	X	X	X	X	H	H	H	H	H	H	H	H
X	H	X	X	X	X	H	H	H	H	H	H	H	H
X	X	L	X	X	X	H	H	H	H	H	H	H	H
L	L	H	L	L	L	L	H	H	H	H	H	H	H
L	L	H	H	L	L	H	L	H	H	H	H	H	H
L	L	H	L	H	L	H	H	L	H	H	H	H	H
L	L	H	H	H	L	H	H	H	L	H	H	H	H
L	L	H	L	L	H	H	H	H	H	L	H	H	H
L	L	H	H	L	H	H	H	H	H	H	L	H	H
L	L	H	L	H	H	H	H	H	H	H	H	L	H
L	L	H	H	H	H	H	H	H	H	H	H	H	L

H = HIGH Voltage Level
L = LOW Voltage Level
X = Immaterial

Logic Diagram



Please note that this diagram is provided only for the understanding of logic operations and should not be used to estimate propagation delays.

Logic Diagram

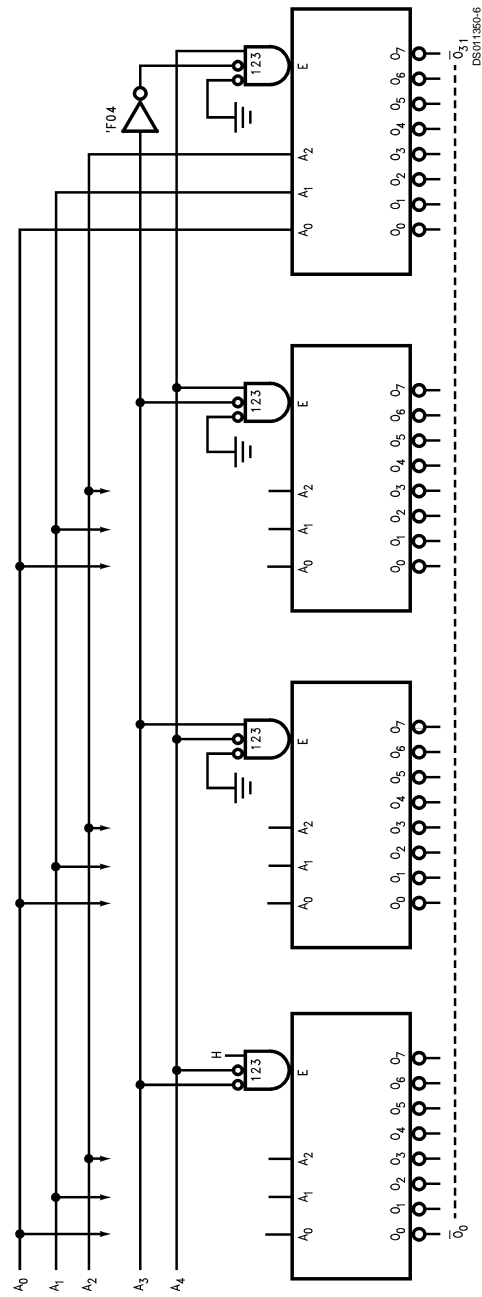


FIGURE 1. Expansion to 1-of-32 Decoding

Absolute Maximum Ratings (Note 1)

Supply Voltage (V_{CC})	-0.5V to +7.0V
DC Input Diode Current (I_{IK})	
$V_I = -0.5V$	-20 mA
$V_I = V_{CC} + 0.5V$	+20 mA
DC Input Voltage (V_I)	-0.5V to $V_{CC} + 0.5V$
DC Output Diode Current (I_{OK})	
$V_O = -0.5V$	-20 mA
$V_O = V_{CC} + 0.5V$	+20 mA
DC Output Voltage (V_O)	-0.5V to $V_{CC} + 0.5V$
DC Output Source	
or Sink Current (I_O)	±50 mA
DC V_{CC} or Ground Current	
(I_{CC} or I_{GND})	±200 mA
Storage Temperature (T_{STG})	-65°C to +150°C
DC Latch-Up Source or	
Sink Current	±300 mA

Recommended Operating Conditions (Note 2)

Supply Voltage (V_{CC})	2.0V to 3.6V
Input Voltage (V_I)	0V to V_{CC}
Output Voltage (V_O)	0V to V_{CC}
Operating Temperature (T_A)	-40°C to +85°C
Minimum Input Edge Rate ($\Delta V/\Delta t$)	
V_{IN} from 0.8V to 2.0V	
V_{CC} @ 3.0V	125 mV/ns

Note 1: The "Absolute Maximum Ratings" are those values beyond which the safety of the device cannot be guaranteed. The device should not be operated at these limits. The parametric values defined in the Electrical Characteristics tables are not guaranteed at the absolute maximum ratings. The "Recommended Operating Conditions" table will define the conditions for actual device operation.

Note 2: Unused inputs must be held HIGH or LOW. They may not float.

DC Electrical Characteristics

Symbol	Parameter	V_{CC} (V)	$T_A = +25^\circ\text{C}$		$T_A = -40^\circ\text{C to } +85^\circ\text{C}$	Units	Conditions
			Typ	Guaranteed Limits			
			V_{IH}	Minimum High Level Input Voltage	3.0		
V_{IL}	Maximum Low Level Input Voltage	3.0	1.5	0.8	0.8	V	$V_{OUT} = 0.1V$ or $V_{CC} - 0.1V$
V_{OH}	Minimum High Level Output Voltage	3.0	2.99	2.9	2.9	V	$I_{OUT} = -50 \mu\text{A}$
		3.0		2.58	2.48	V	$V_{IN} = V_{IL}$ or V_{IH} (Note 3) $I_{OH} = -12 \text{ mA}$
V_{OL}	Maximum Low Level Output Voltage	3.0	0.002	0.1	0.1	V	$I_{OUT} = 50 \mu\text{A}$
		3.0		0.36	0.44	V	$V_{IN} = V_{IL}$ or V_{IH} (Note 3) $I_{OL} = 12 \text{ mA}$
I_{IN}	Maximum Input Leakage Current	3.6		±0.1	±1.0	μA	$V_I = V_{CC}, \text{GND}$
I_{OLD}	Minimum Dynamic (Note 4)	3.6			36	mA	$V_{OLD} = 0.8V$ Max (Note 5)
I_{OH}	Output Current	3.6			-25	mA	$V_{OHD} = 2.0V$ Min (Note 5)
I_{CC}	Maximum Quiescent Supply Current	3.6		4.0	40.0	μA	$V_{IN} = V_{CC}$ or GND
V_{OLP}	Quiet Output Maximum Dynamic V_{OL}	3.3		0.8		V	(Notes 6, 7)
V_{OLV}	Quiet Output Minimum Dynamic V_{OL}	3.3		-0.8		V	(Notes 6, 7)
V_{IHD}	Maximum High Level Dynamic Input Voltage	3.3	1.7	2.0		V	(Notes 6, 8)
V_{ILD}	Maximum Low Level Dynamic Input Voltage	3.3	1.7	0.8		V	(Notes 6, 8)

Note 3: All outputs loaded; thresholds on input associated with output under test.

Note 4: Maximum test duration 2.0 ms, one output loaded at a time.

Note 5: Incident wave switching on transmission lines with impedances as low as 75Ω for commercial temperature range is guaranteed.

Note 6: Worst case package.

Note 7: Max number of outputs defined as (n). Data inputs are driven 0V to 3.3V; one output at GND.

Note 8: Max number of Data Inputs (n) switching. (n - 1) inputs switching 0V to 3.3V. Input-under-test switching: 3.3V to threshold (V_{ILD}), 0V to threshold (V_{IHD}), $f = 1 \text{ MHz}$.

AC Electrical Characteristics

Symbol	Parameter	V _{CC} (V)	T _A = +25°C C _L = 50 pF			T _A = -40°C to +85°C C _L = 50 pF		Units
			Min	Typ	Max	Min	Max	
t _{PLH}	Propagation Delay	2.7	1.5	10.2	18.3	1.5	21.0	ns
	A _n to \bar{O}_n	3.3 ±0.3	1.5	8.5	13.0	1.5	15.0	
t _{PHL}	Propagation Delay	2.7	1.5	9.6	17.6	1.5	20.0	ns
	A _n to \bar{O}_n	3.3 ±0.3	1.5	8.0	12.5	1.5	14.0	
t _{PLH}	Propagation Delay	2.7	1.5	13.2	21.0	1.5	23.0	ns
t _{PHL}	Propagation Delay	2.7	1.5	11.4	19.0	1.5	21.0	ns
	\bar{E}_1 or \bar{E}_2 to \bar{O}_n	3.3 ±0.3	1.5	9.5	13.5	1.5	15.0	
t _{PLH}	Propagation Delay	2.7	1.5	13.2	21.8	1.5	23.5	ns
t _{PHL}	Propagation Delay	2.7	1.5	10.2	18.3	1.5	20.0	ns
	E ₃ to \bar{O}_n	3.3 ±0.3	1.5	11.0	15.5	1.5	16.5	
t _{OSHL}	Output to Output Skew (Note 9)	2.7		1.0	1.5		1.5	ns
t _{OSLH}	Data to Output	3.3 ±0.3		1.0	1.5		1.5	

Note 9: Skew is defined as the absolute value of the difference between the actual propagation delay for any two separate outputs of the same device. The specification applies to any outputs switching in the same direction, either HIGH to LOW (t_{OSHL}) or LOW to HIGH (t_{OSLH}). Parameter guaranteed by design.

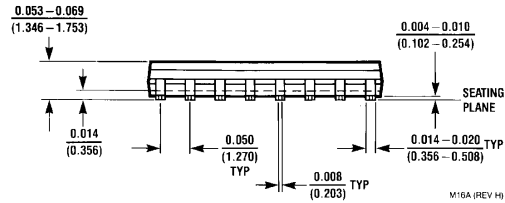
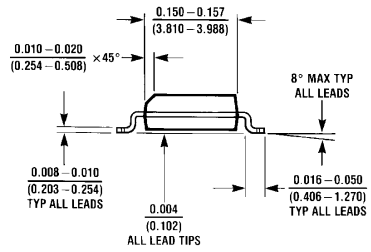
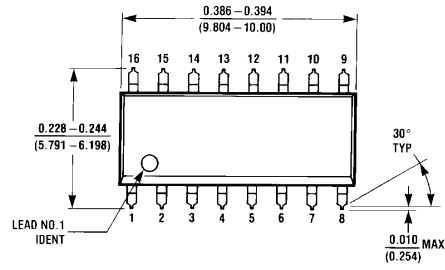
Capacitance

Symbol	Parameter	Typ	Units	Conditions
C _{IN}	Input Capacitance	4.5	pF	V _{CC} = Open
C _{PD} (Note 10)	Power Dissipation Capacitance	45	pF	V _{CC} = 3.3V

Note 10: C_{PD} is measured at 10 MHz.

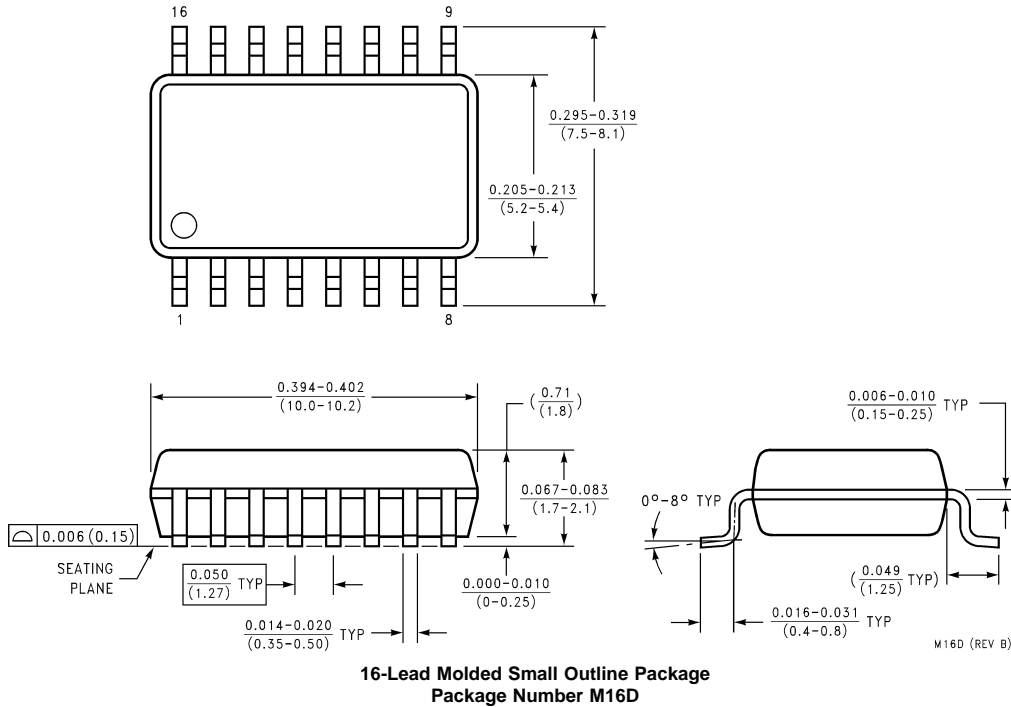


Physical Dimensions inches (millimeters) unless otherwise noted



**16-Lead (0.150" Wide) Small Outline Integrated Circuit
Package Number M16A**

Physical Dimensions inches (millimeters) unless otherwise noted (Continued)



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